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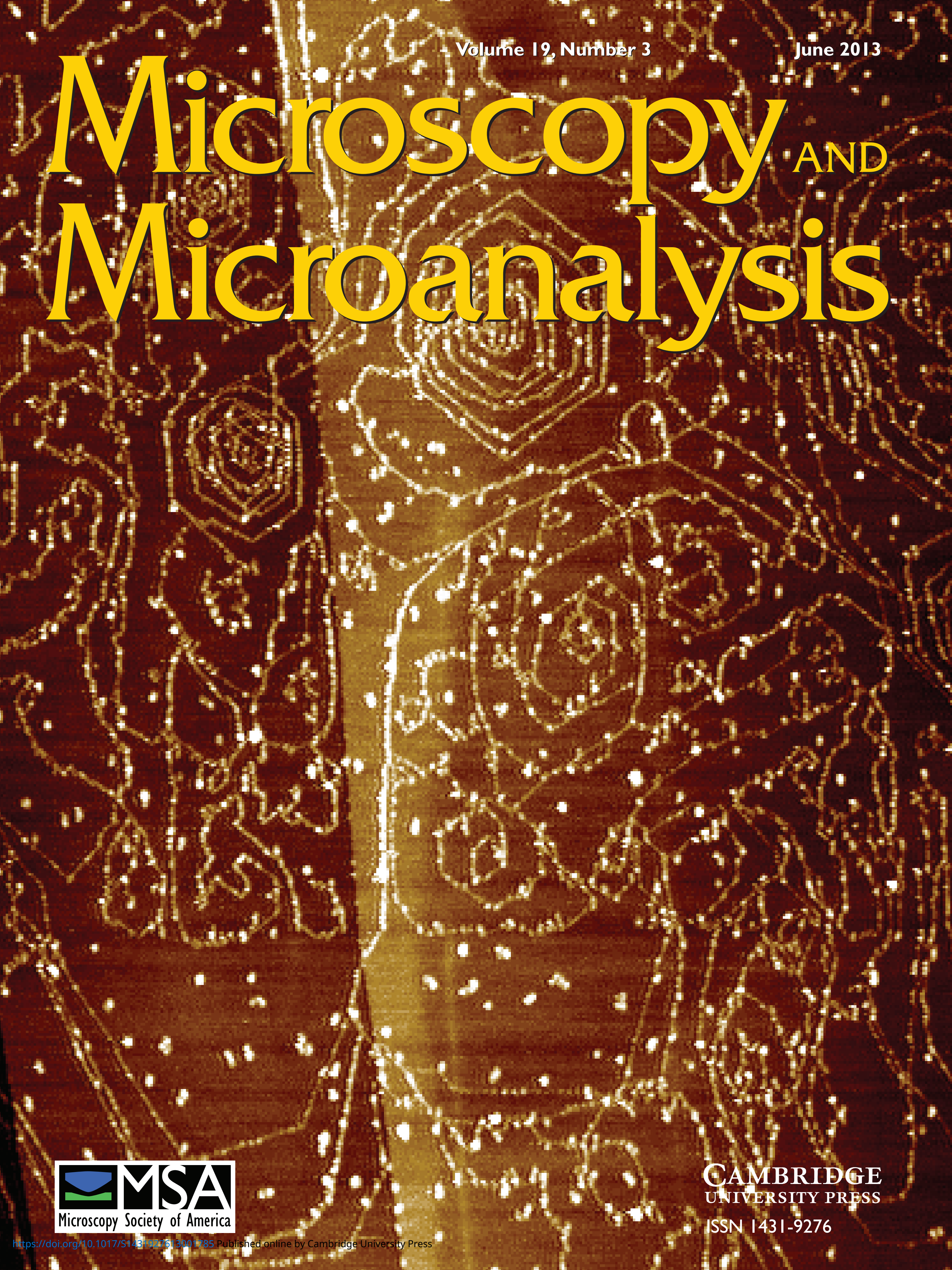

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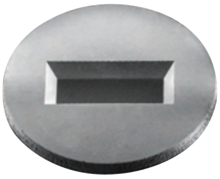

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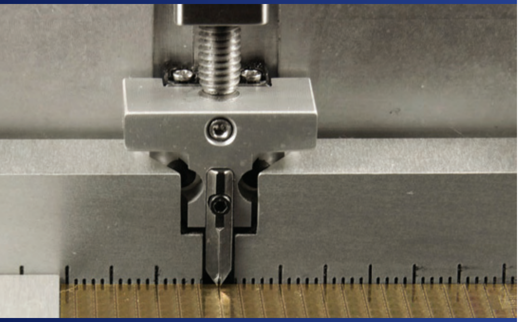

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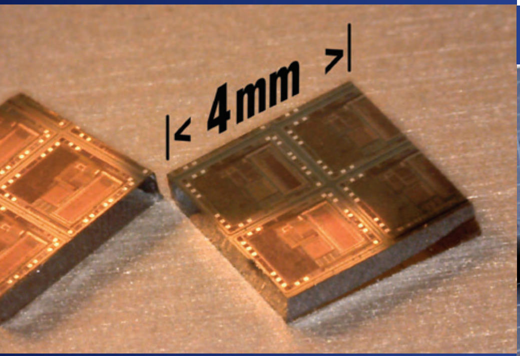

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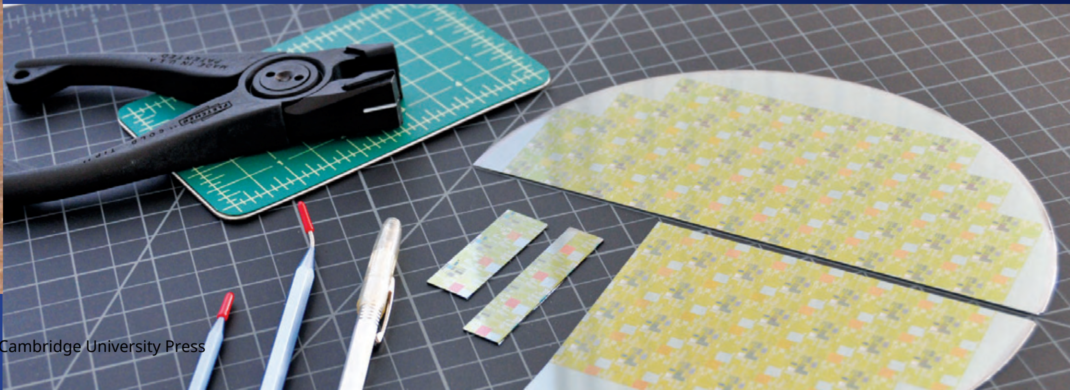

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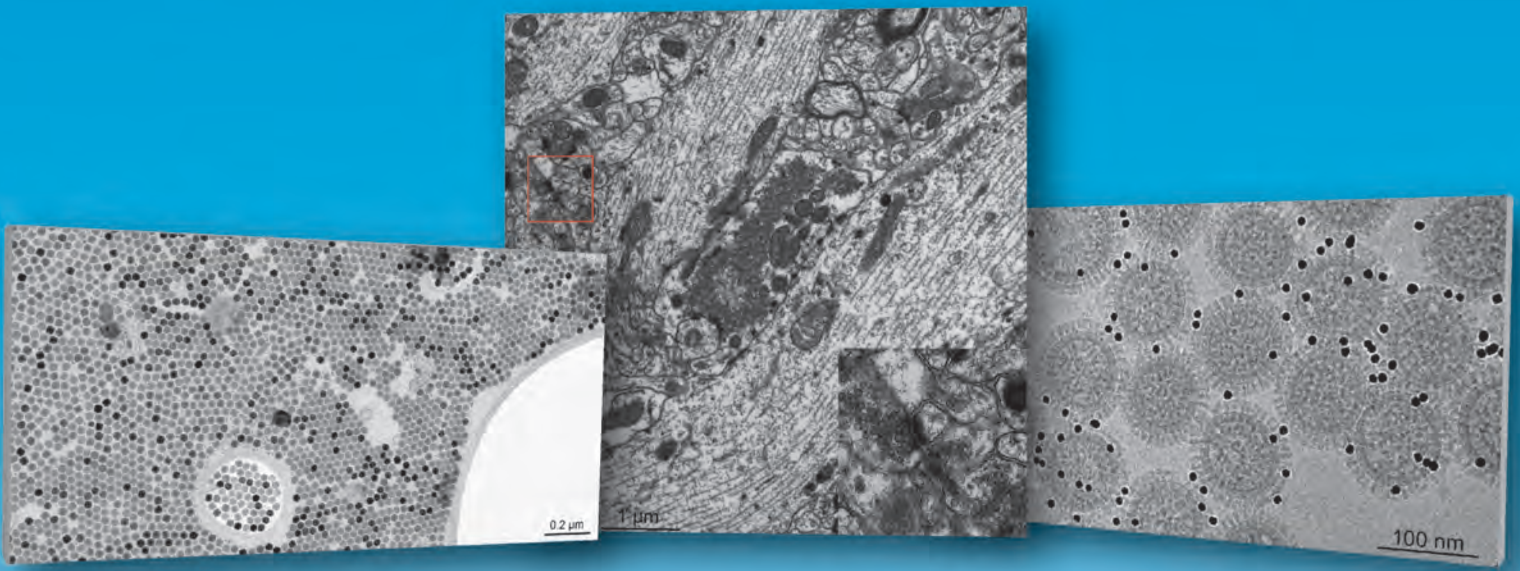

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- Nano-crystals recorded with Gatan UltraScan®1000XP CCD camera on a 120 kV TEM. Image courtesy of the University of California - Berkeley, Dr. Kent McDonald.
- Mouse Hippocampus recorded with Gatan UltraScan®4000 CCD Camera on a 100 kV TEM. Sample courtesy of Mr. Y. Satoh of JEOL, Ltd.
- Frozen hydrated influenza virus prepared using Cryoplunge™3. Gold particles were added as fiducial markers for cryo electron tomography. Zero loss image was recorded at TEM magnification of 50kX and electron dose of $\sim 20\ e^-/\text{Å}^2$ at 300 keV using Gatan Ultrascan®4000 CCD camera. Sample was prepared on Quantifoil® (2/2) specimen support, using Gatan Solarus®950 Advanced Plasma Cleaning System prior to freezing. Image courtesy of Dr. Ruben Diaz-Avalos, New York Structural Biology Center, NY, USA.

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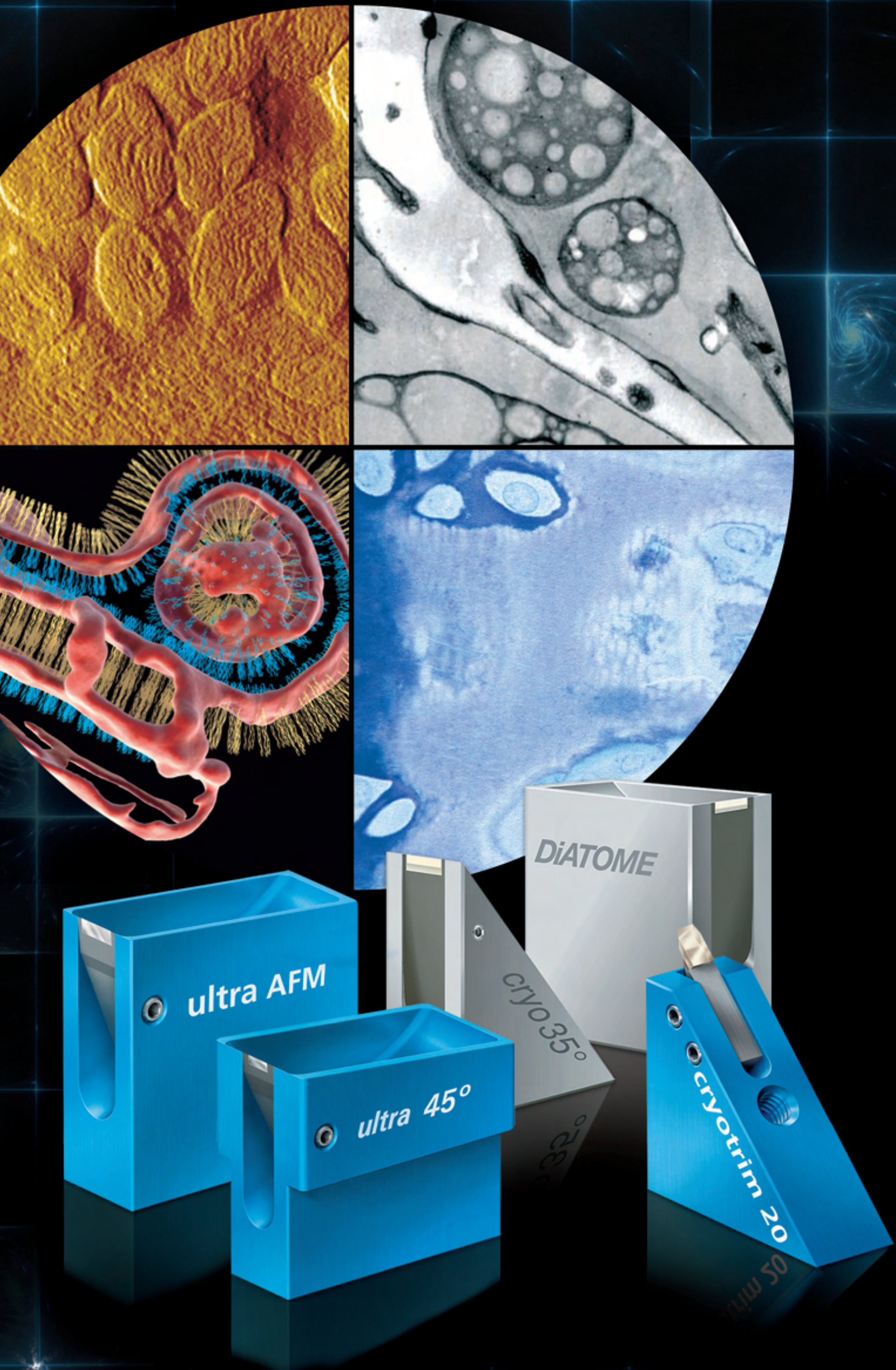

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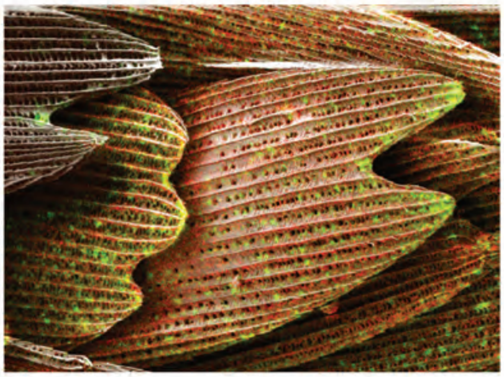
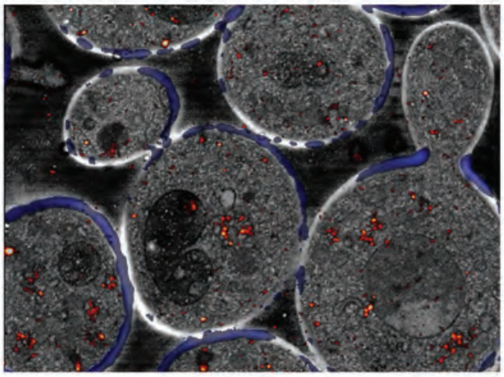

Correlative microscopy with confocal and SEM of a butterfly wing. Green: reflection; red: auto fluorescence.


Correlative microscopy with superresolution dSTORM and SEM of yeast. Calcofluor (blue, cell wall); red: G protein coupled receptor (GPCR), localized in vesicular structures.

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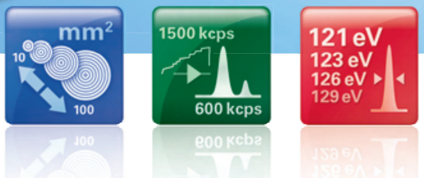

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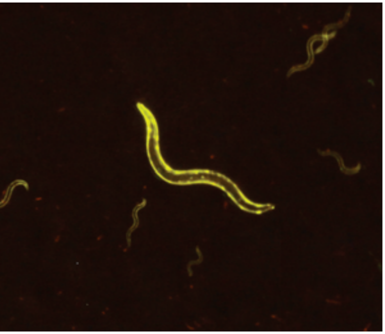
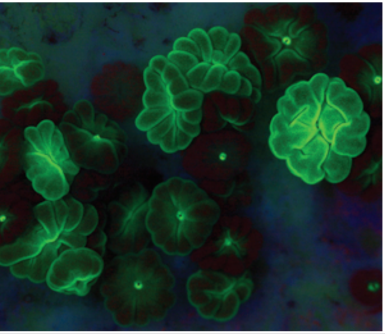


Fluorescing YFP-transgenic *C. elegans* photographed using the NIGHTSEA Stereo Microscope Fluorescence Adapter. Photograph © NIGHTSEA/Charles Mazel

GFP-tagged *Drosophila* larva. Photograph © NIGHTSEA/ Charles Mazel



Coral Polyps — Fluorescence. © Wade Cooper

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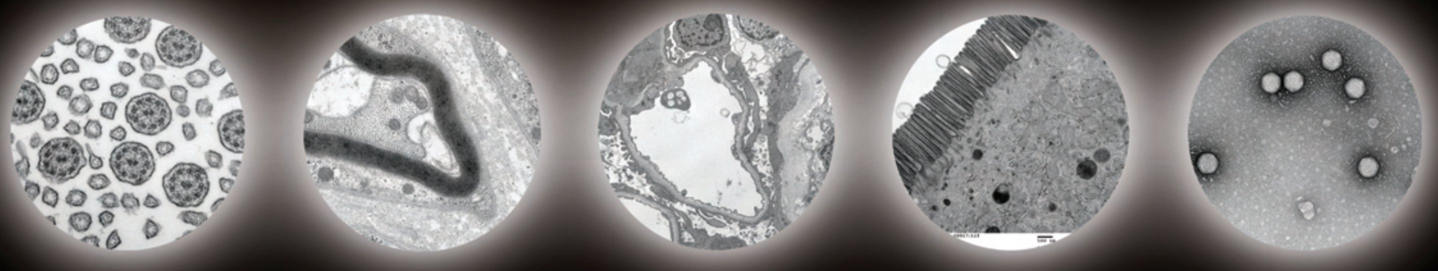

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